

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/747,639	ERICKSON ET AL.		
Examiner	Art Unit		
EDMUND H. LEE	1791		

SEARCHED					
Class	Subclass	Date	Examiner		
UPDATED		10/26/2007	EHL		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
UPDATED	10/26/2007	EHL	
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